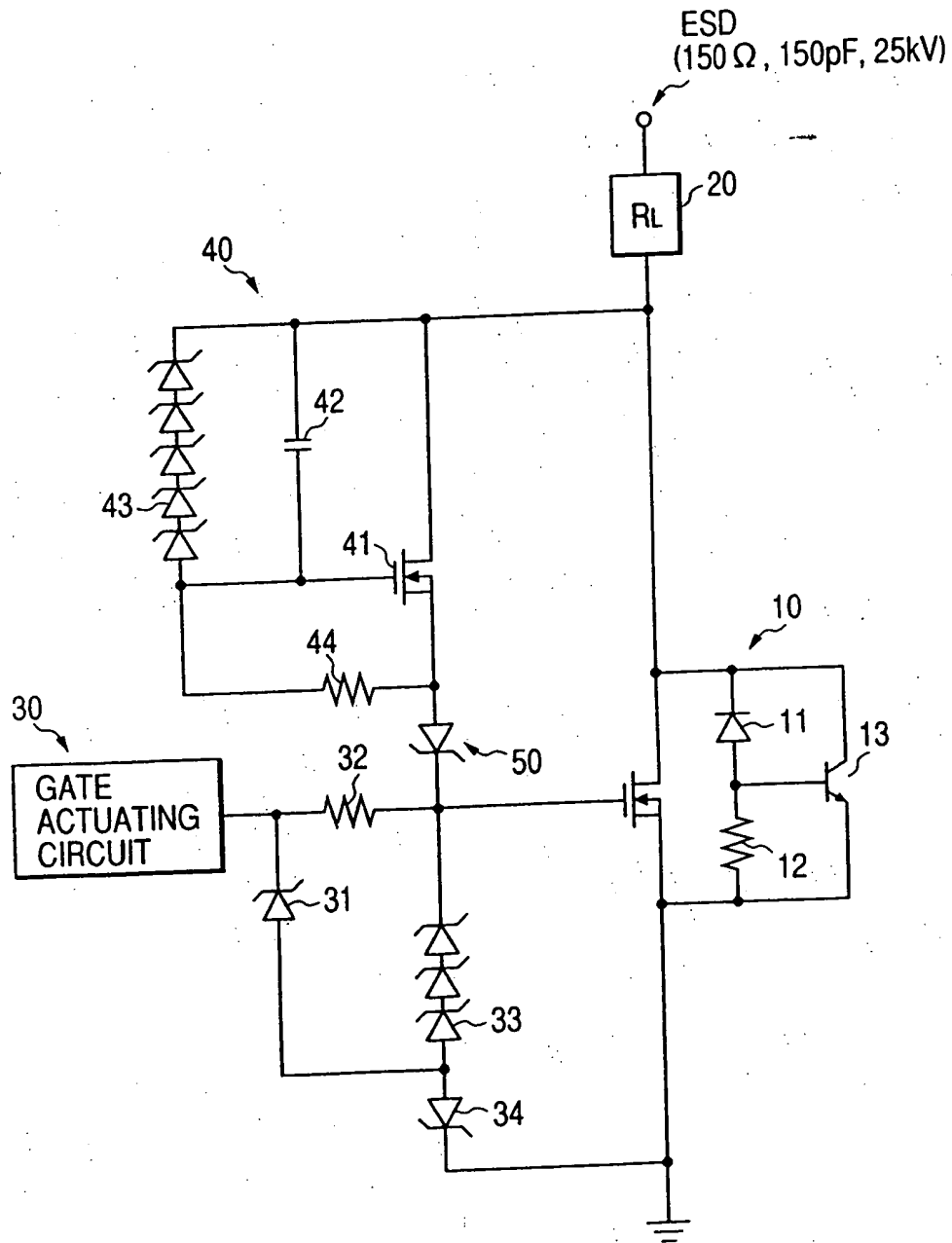




1 / 29

FIG. 1



2 / 29

FIG. 2A

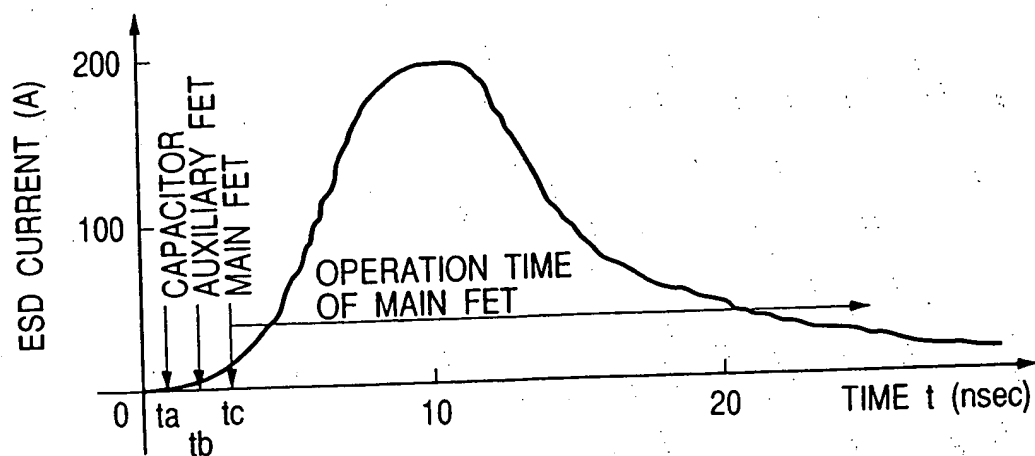
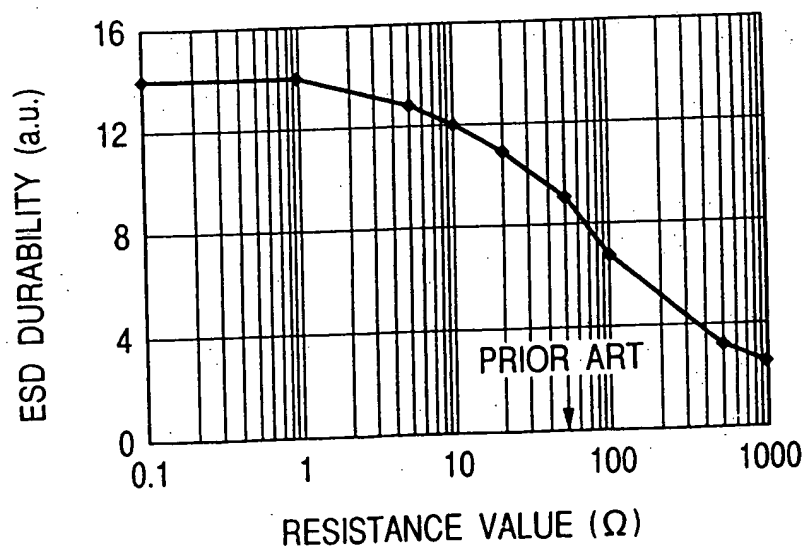
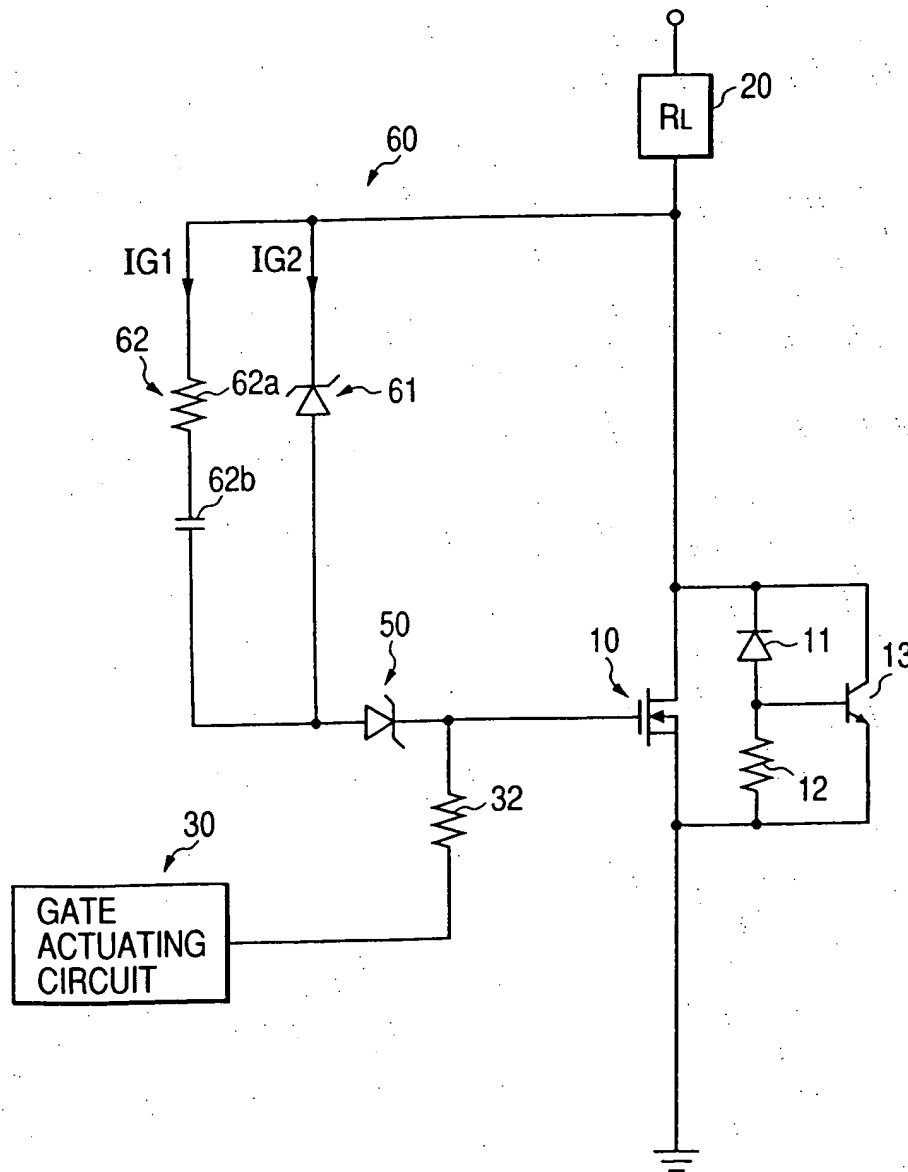


FIG. 2B



3/29

FIG. 3



4 / 29

FIG. 4

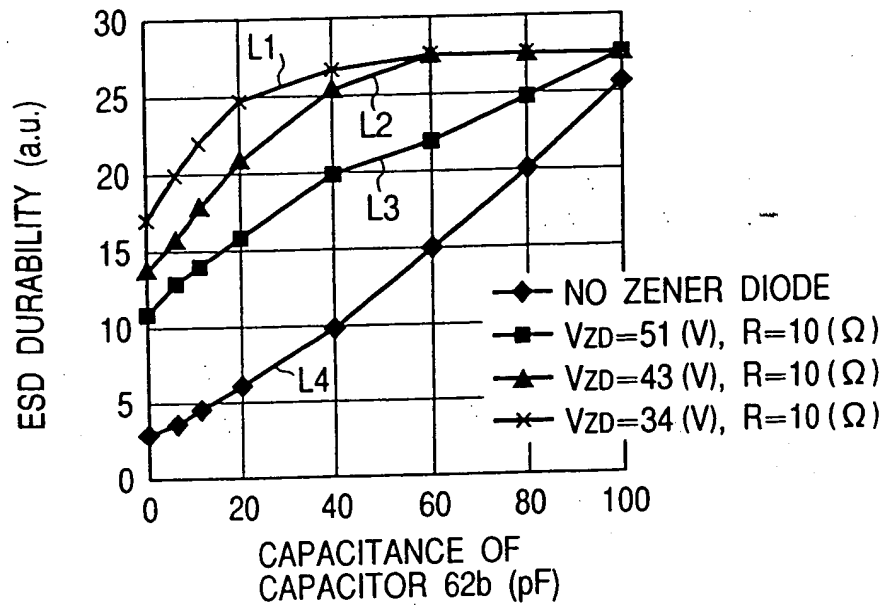
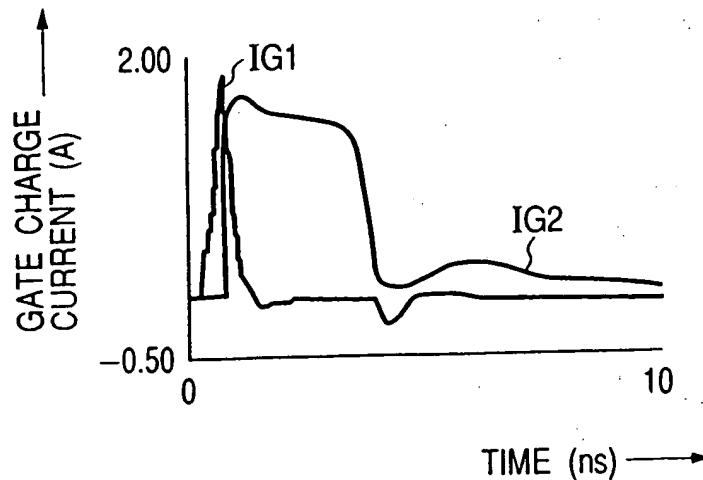
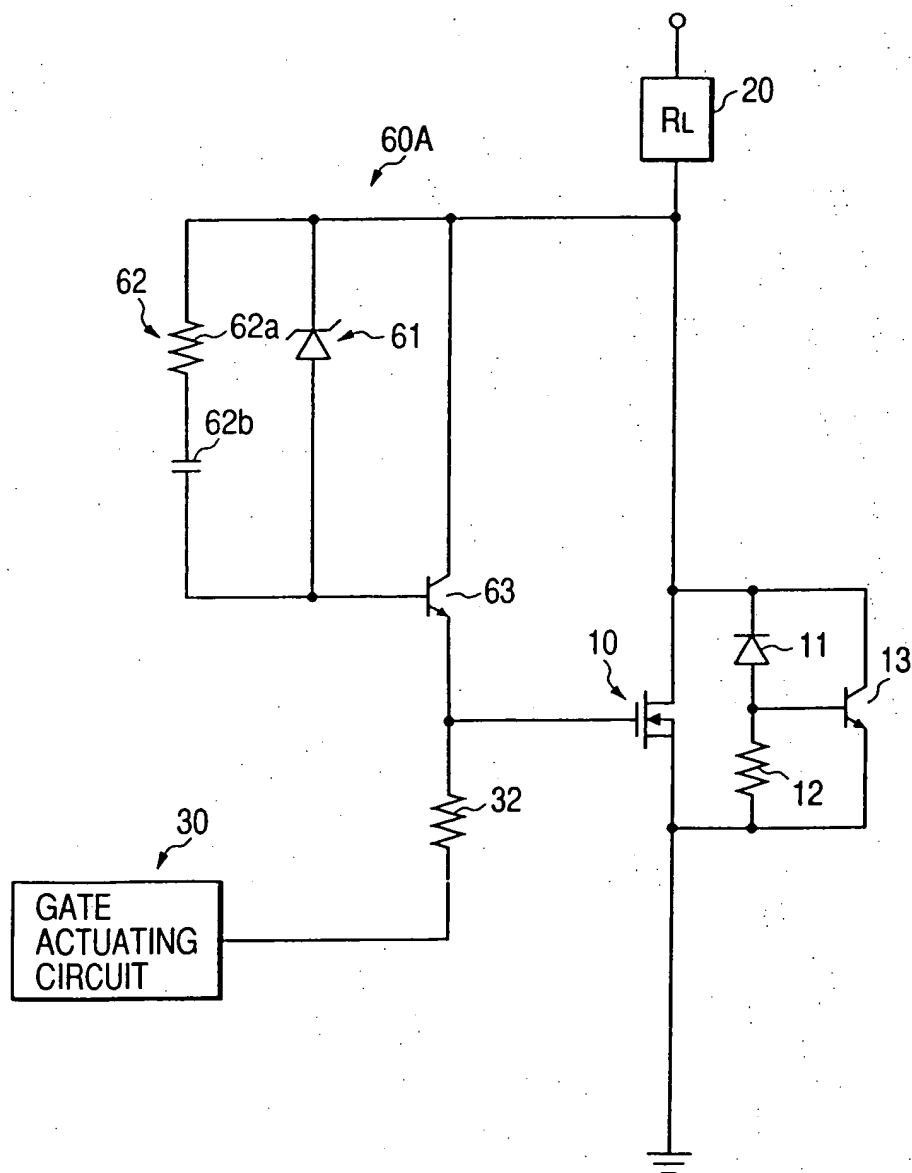


FIG. 5



5 / 29

FIG. 6



[illegible]

7/29

FIG. 8

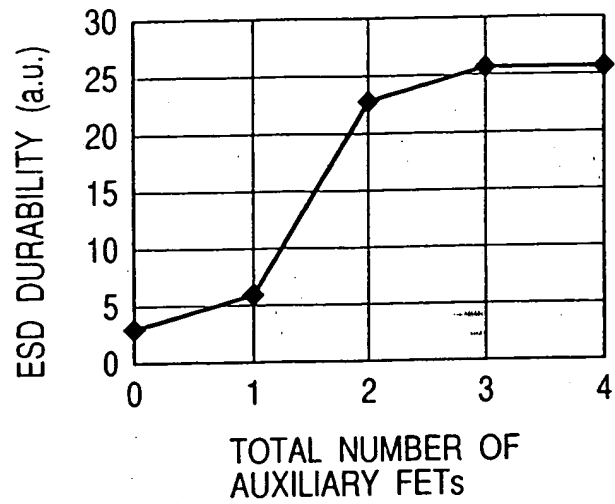


FIG. 10

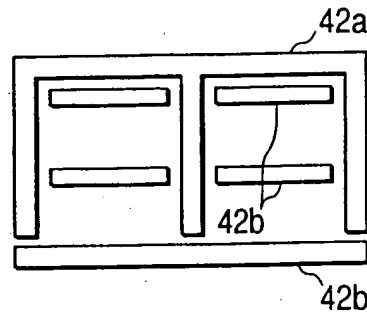
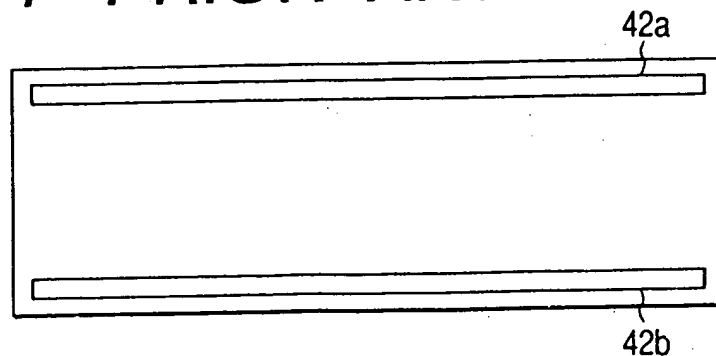
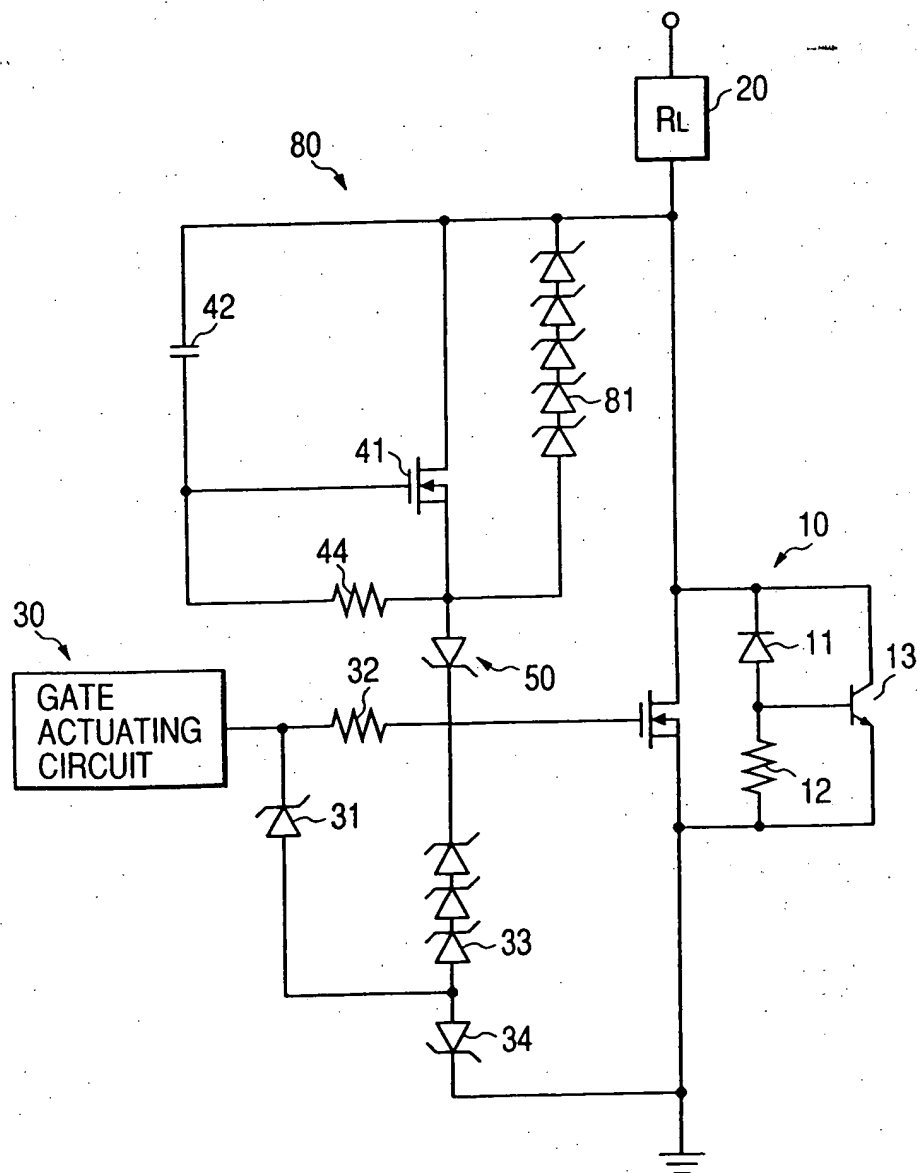


FIG. 11 PRIOR ART



8/29

FIG. 9



9/29

FIG. 12A

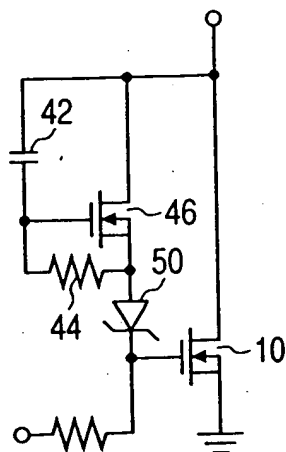


FIG. 12B

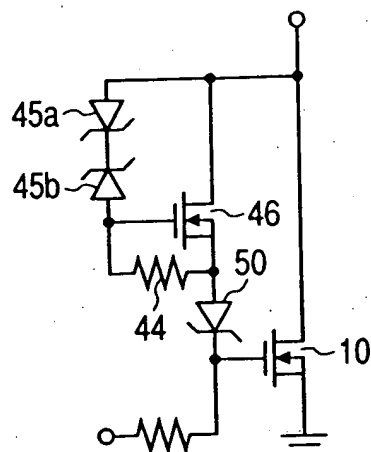


FIG. 14

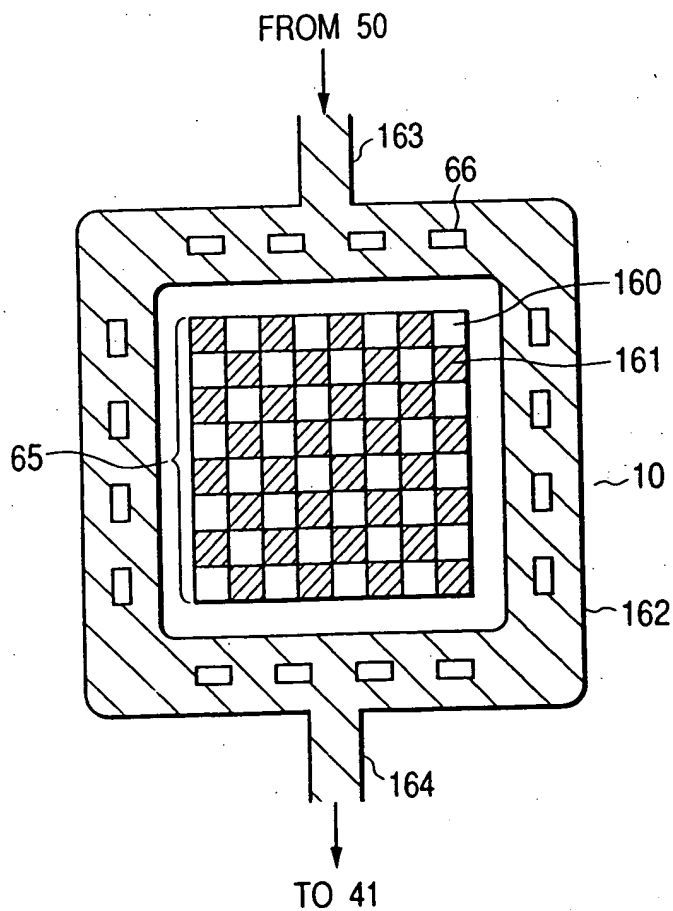


FIG. 1 is a plan view of a semiconductor chip. The chip contains a central array of FETs 10. Each FET 10 has a drain 46 and a source 50. The array is surrounded by pads 42. Labels include CHIP, PAD, 42, FET 10, 13b, 46, DRAIN, SOURCE, and 50.

11 / 29

FIG. 15A

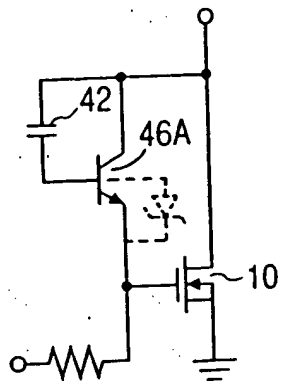


FIG. 15B

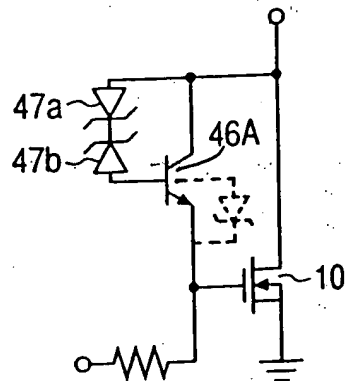


FIG. 16A

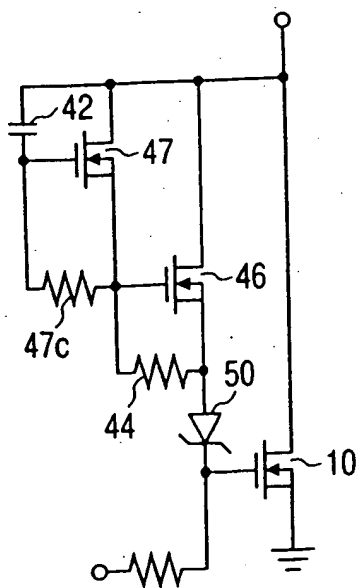
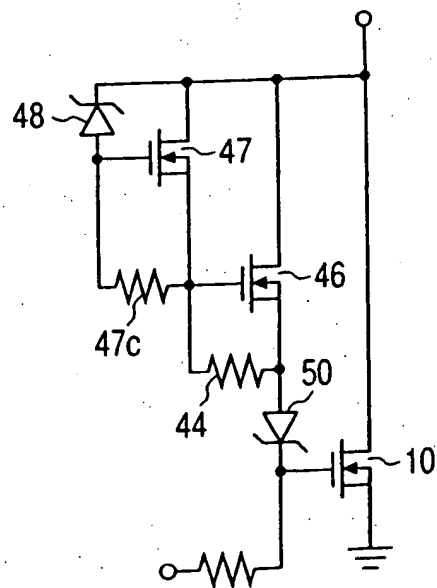


FIG. 16B



12/29

FIG. 17A

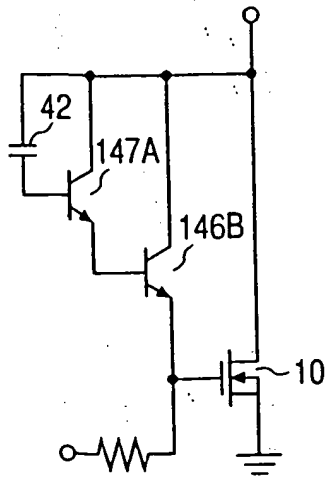


FIG. 17B

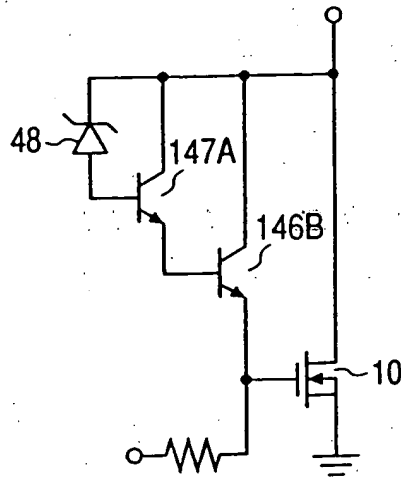


FIG. 18A

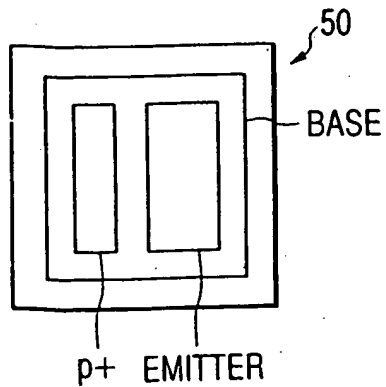
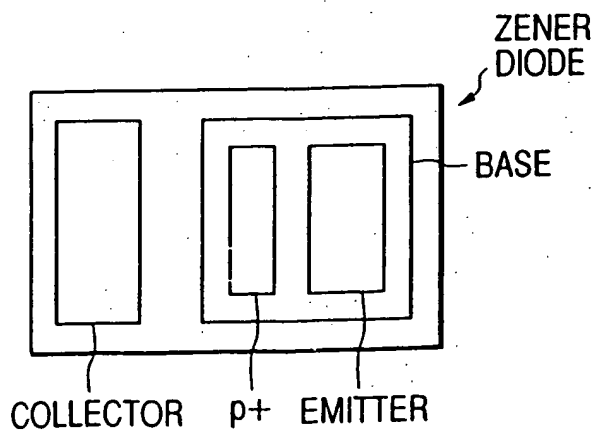
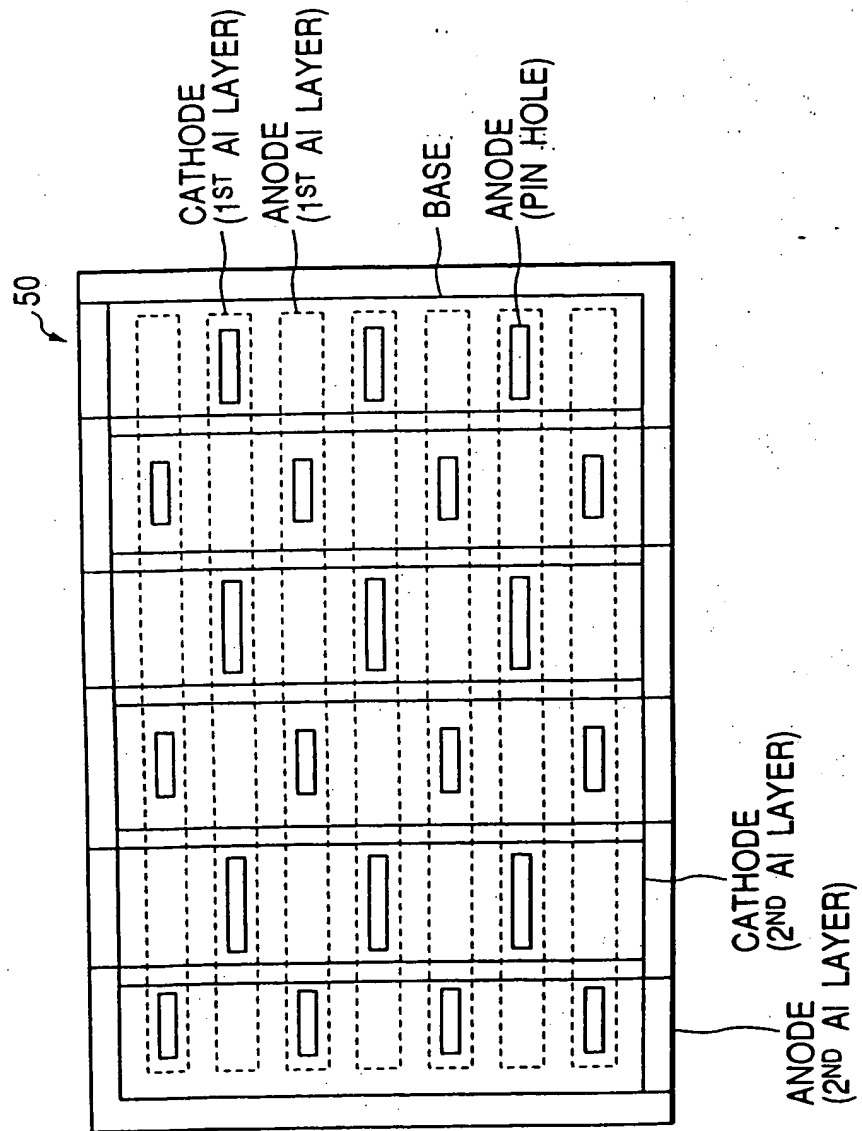


FIG. 18B
PRIOR ART



13 / 29

FIG. 19



14 / 29

FIG. 20A

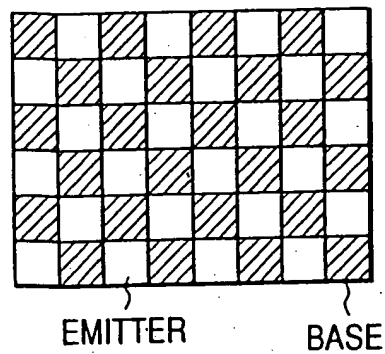


FIG. 20B

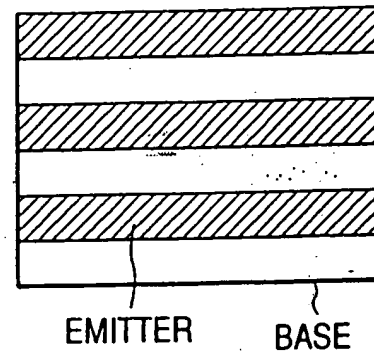
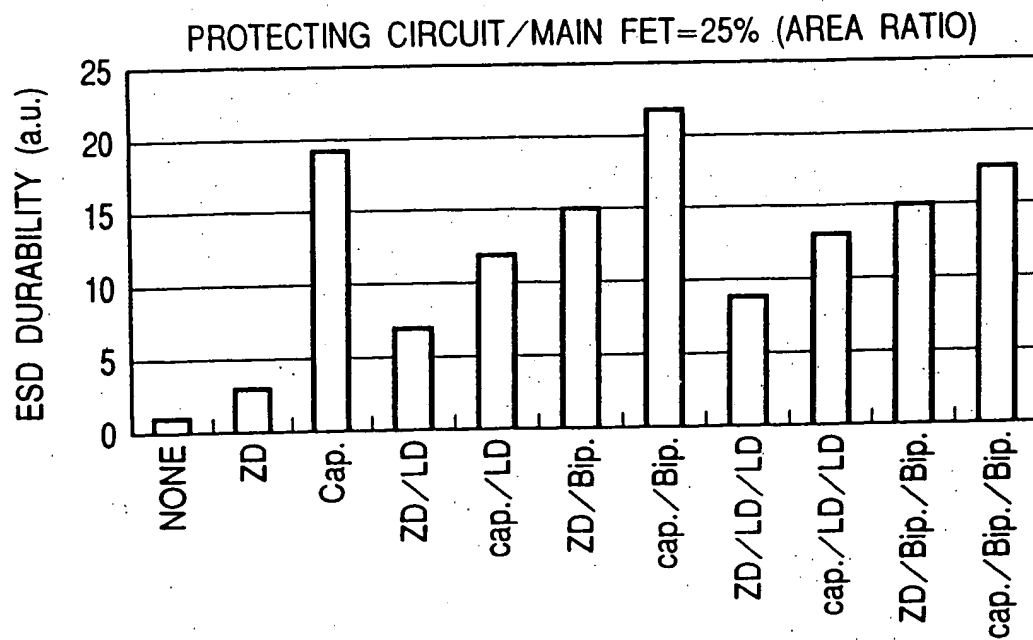
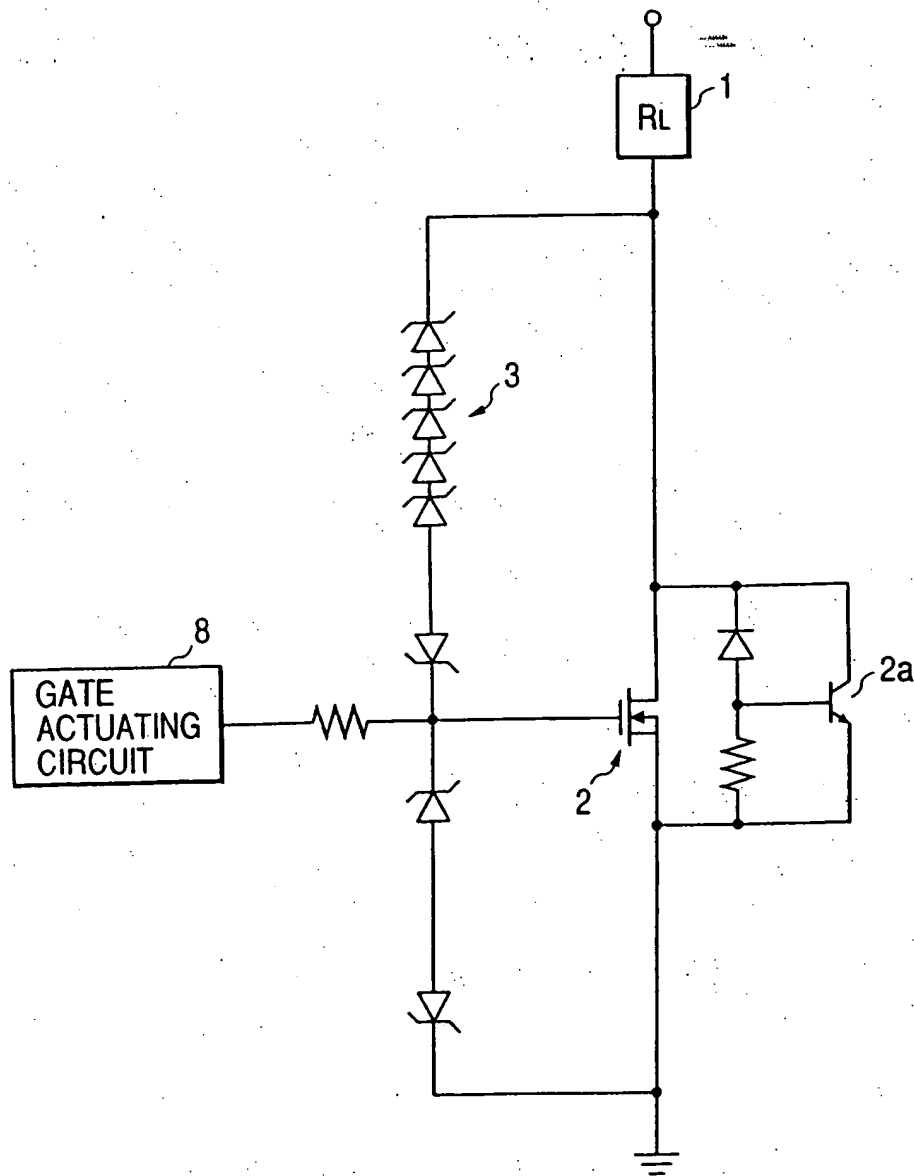


FIG. 21



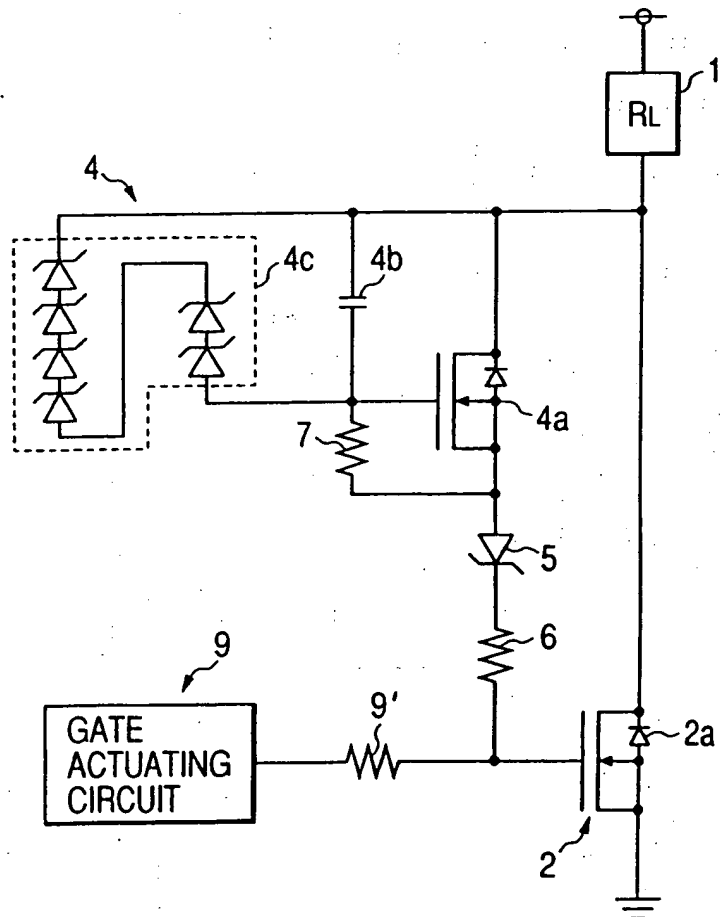
15/29

FIG. 22 PRIOR ART



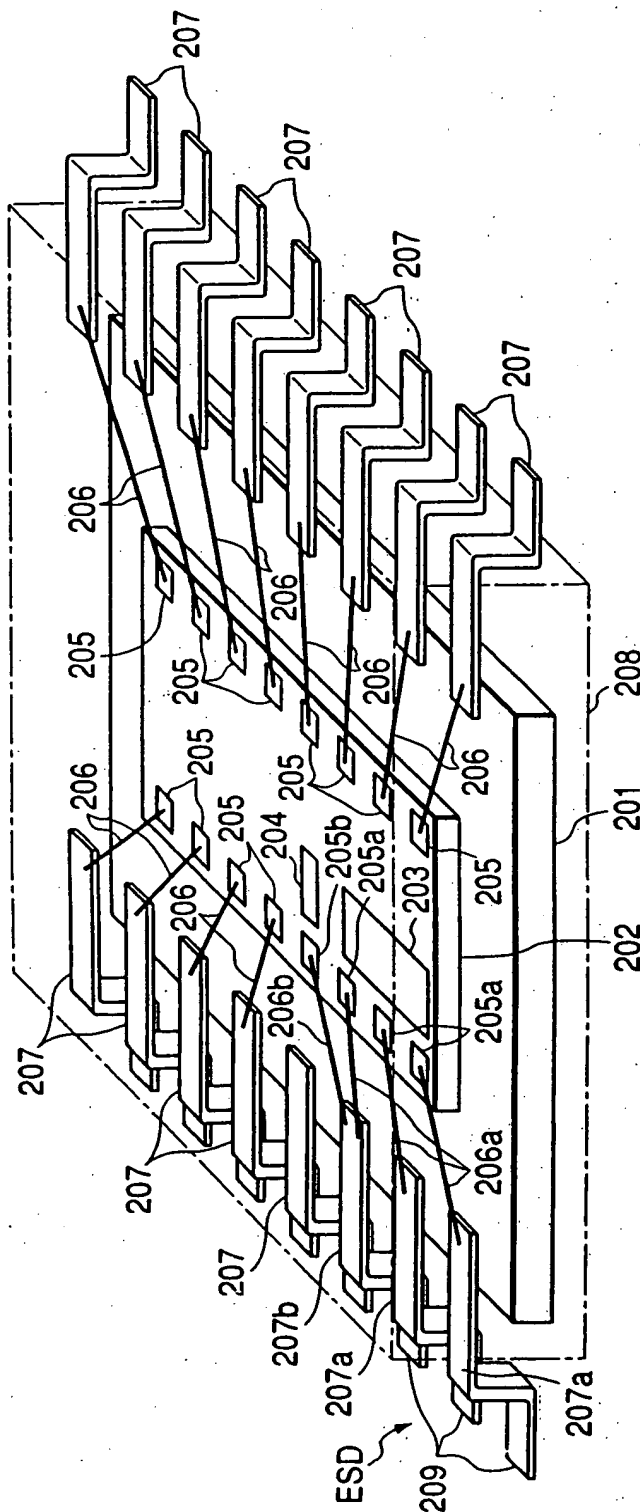
16 / 29

FIG. 23 PRIOR ART



17 / 29

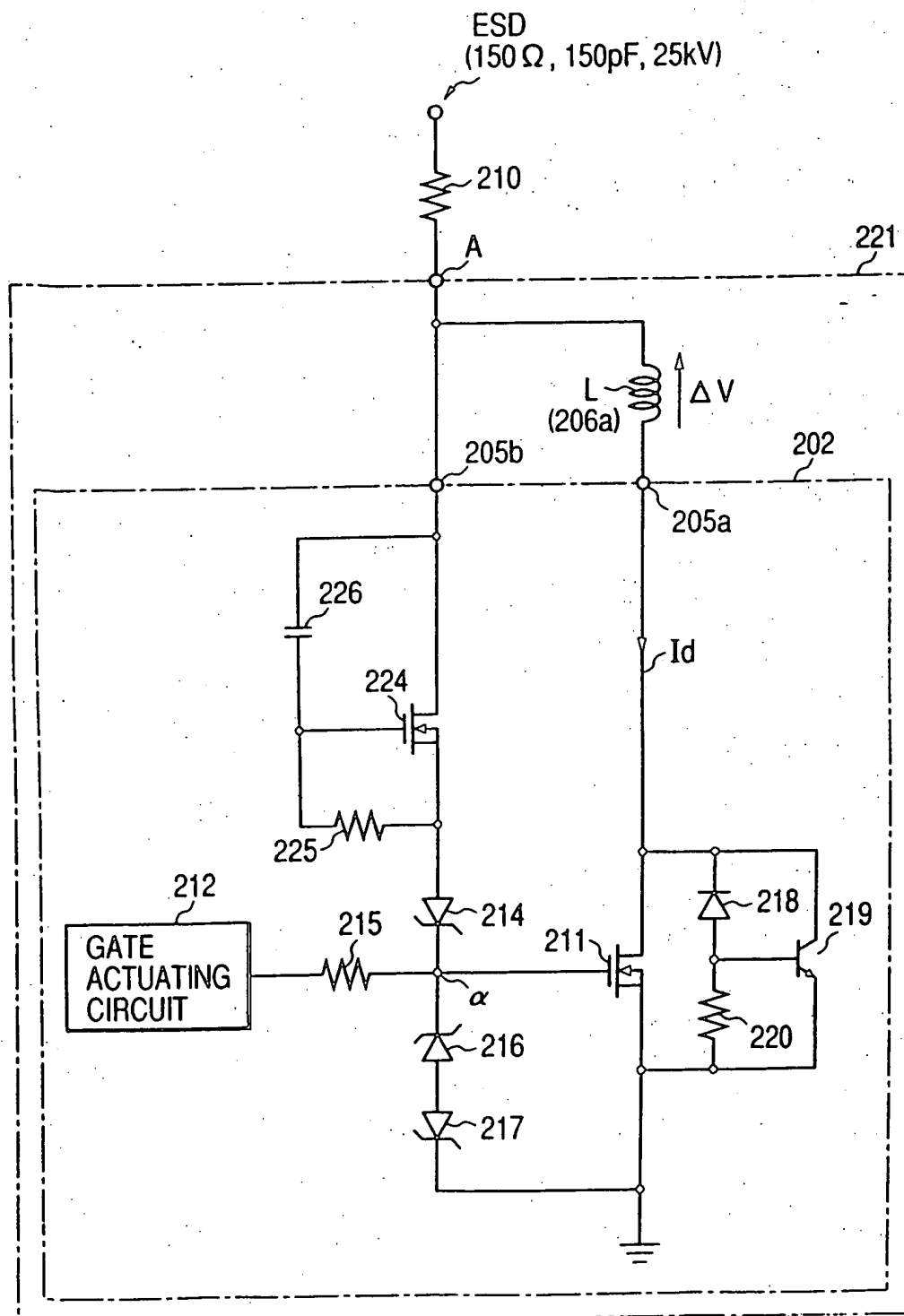
FIG. 24



The diagram illustrates a gate actuating circuit (212) designed for ESD protection. The circuit includes a gate driver (219) consisting of a PMOS transistor (211) and an NMOS transistor (219) with a load resistor (220). The gate of the PMOS transistor (211) is connected to a gate resistor (215) and a series stack of diodes (214, 216, 217) connected to ground. A dashed box (213) encloses a series stack of five diodes connected to the gate of the NMOS transistor (219). The circuit is protected by an ESD protection network (210) connected to a terminal (A) and a series inductor (206a) connected to a node (205b). A voltage source (202) is connected to node (205b) through a resistor (205a) and a diode (Id). A voltage difference (ΔV) is indicated across the inductor (206a).

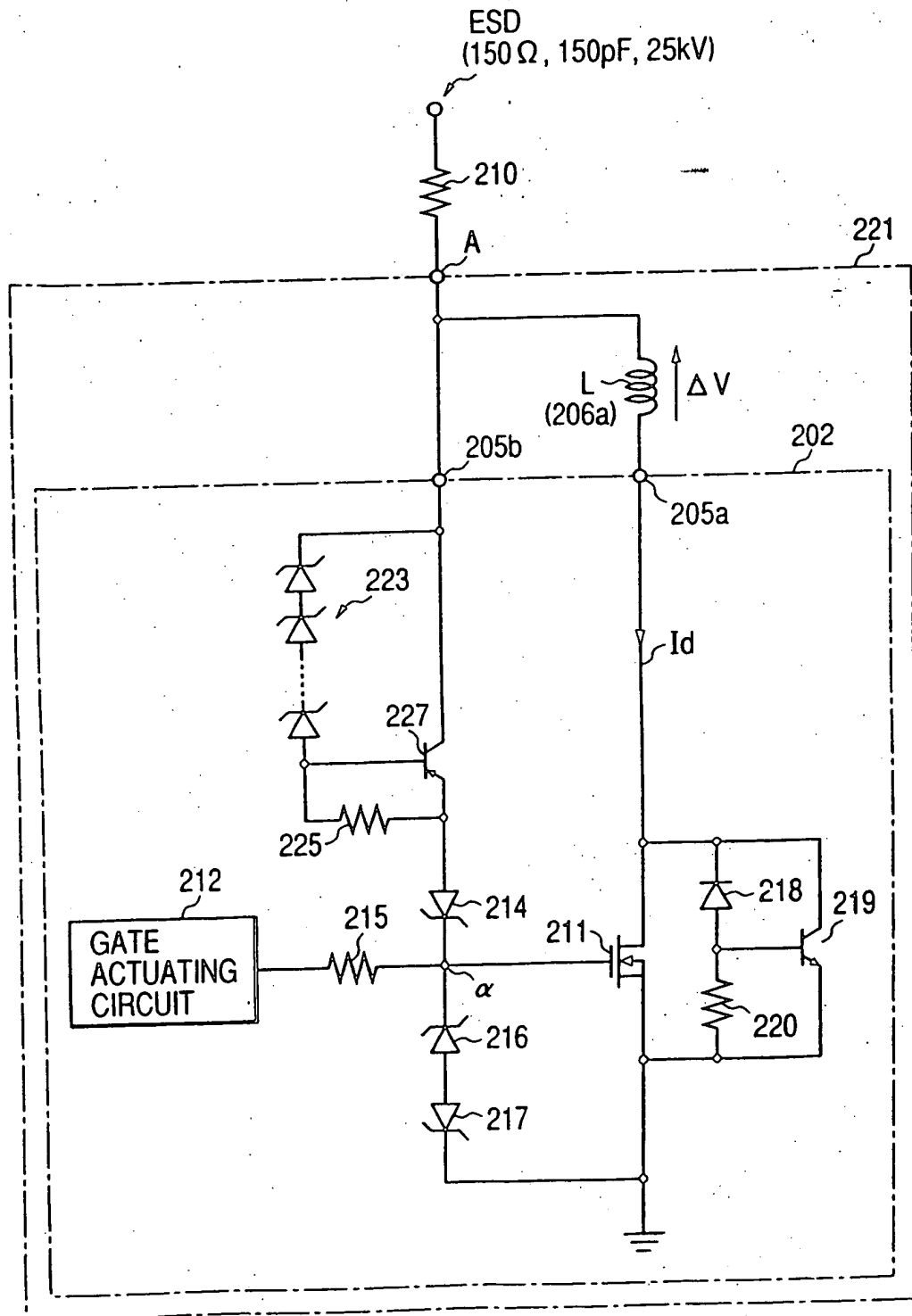
The diagram illustrates an ESD protection circuit for a semiconductor device. An ESD source, characterized by a resistance of 150 Ω, a capacitance of 150 pF, and a voltage of 25 kV, is connected to a node A. Node A is connected to a resistor 210. The circuit is divided into two main sections by a dashed line 221. The upper section, labeled 202, contains an inductor L (206a) connected to node A and a node 205b. A voltage difference ΔV is indicated across the inductor. The lower section, labeled 222, contains a diode stack 223, a transistor 224, and a resistor 225. A gate actuating circuit 212 is connected to a resistor 215, which is in turn connected to a node α. Node α is connected to a diode 214, a transistor 211, and a diode 216. A diode 217 is connected to node α and ground. A node 205a is connected to the inductor L and a diode Id. A diode 218 and a resistor 220 are connected to node 205a and ground. A transistor 219 is connected to node 205a and ground.

FIG. 27



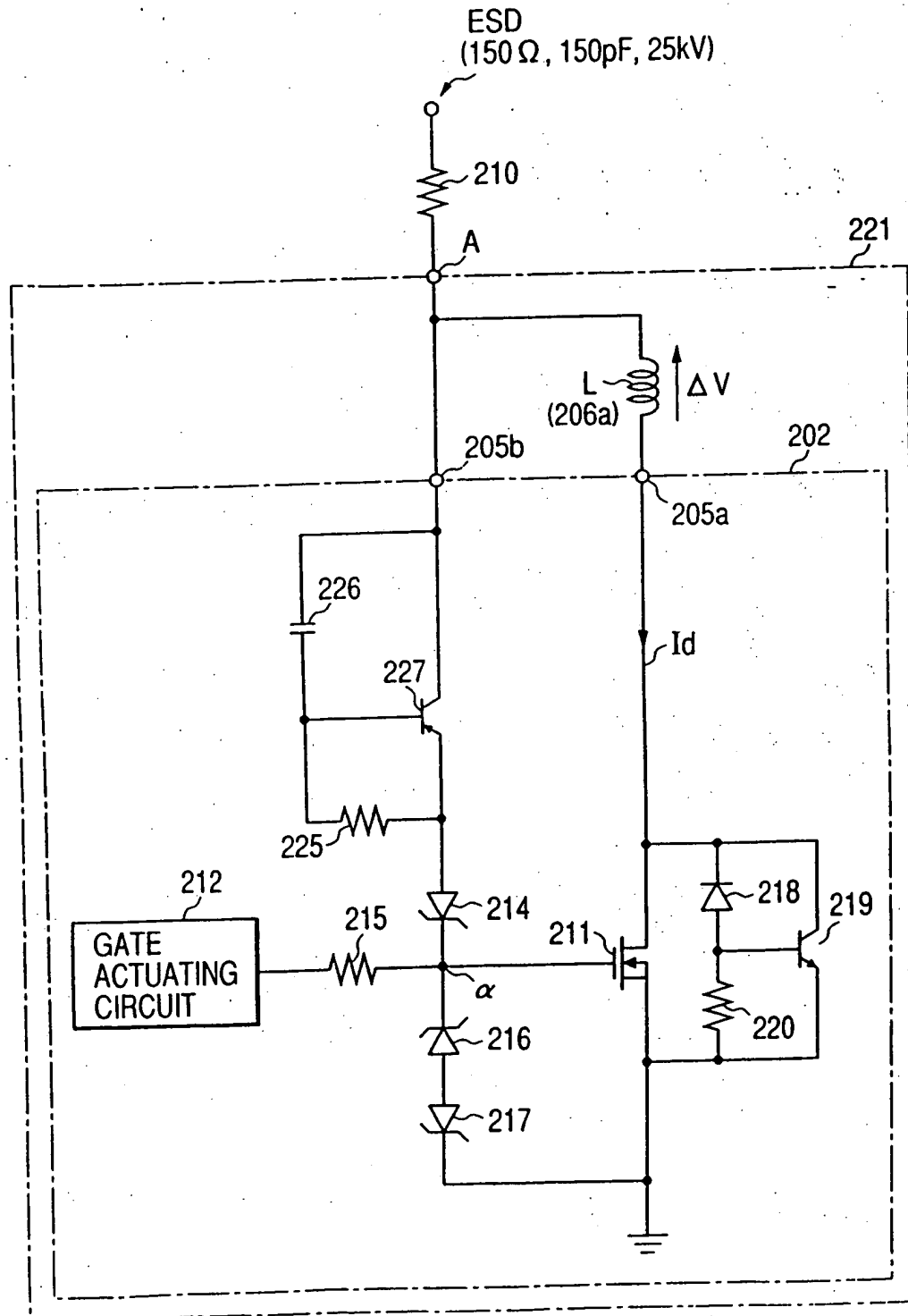
21 / 29

FIG. 28



22 / 29

FIG. 29



ESD
(150 Ω , 150pF, 25kV)

210

A

221

205b

L (206a)

ΔV

202

205a

223

226

214

212

GATE ACTUATING CIRCUIT

215

211

α

216

217

218

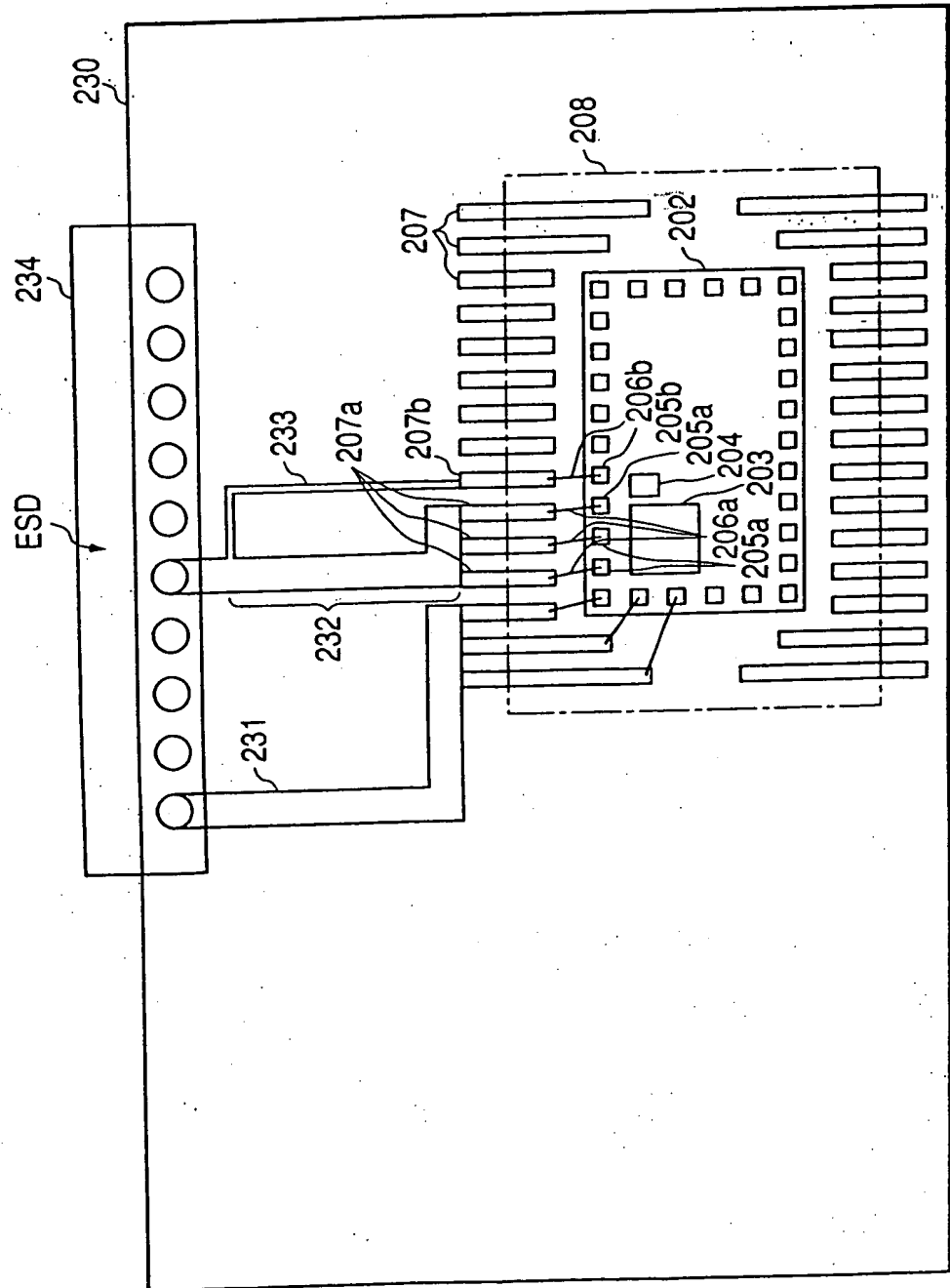
220

219

I_d

24 / 29

FIG. 31



25 / 29

FIG. 32A

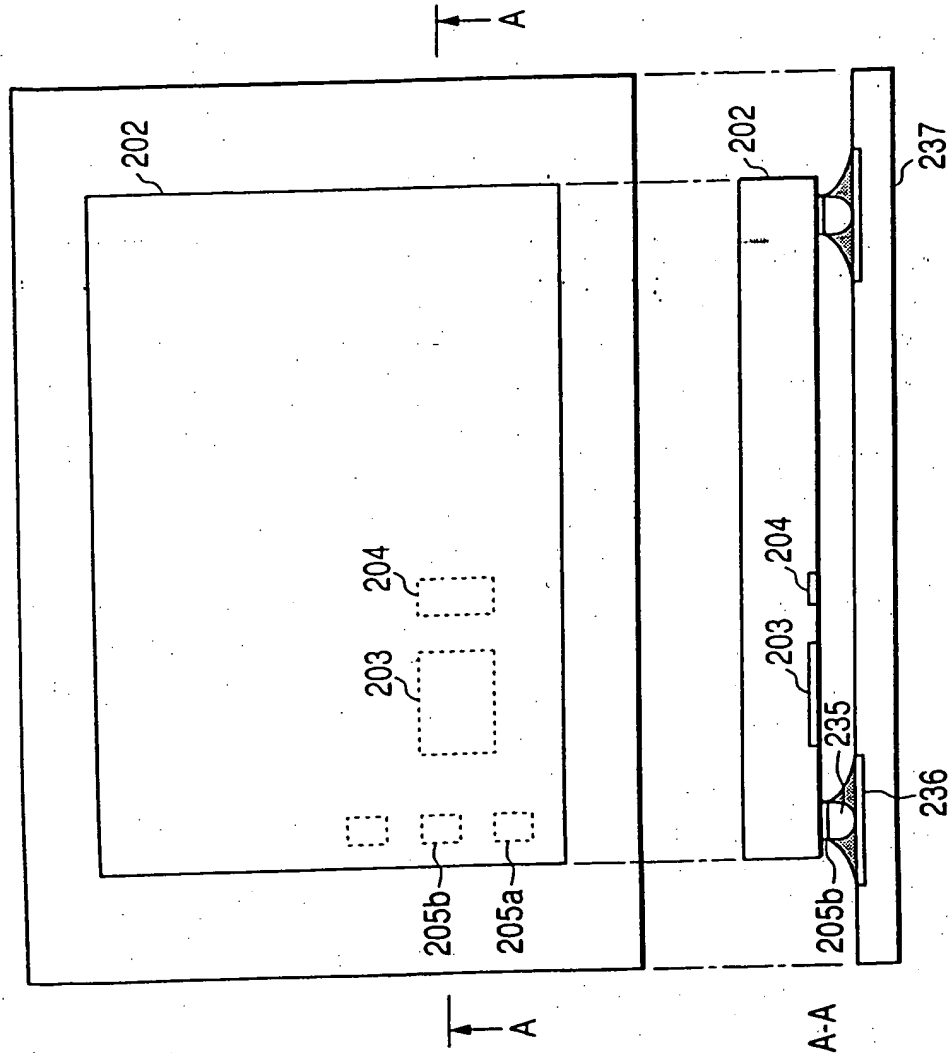
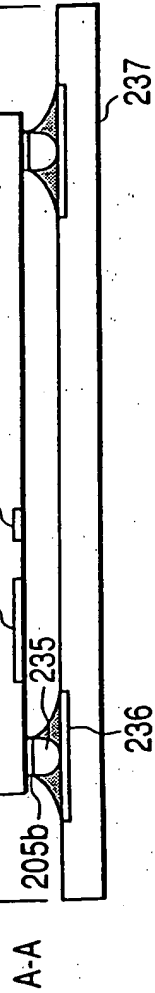
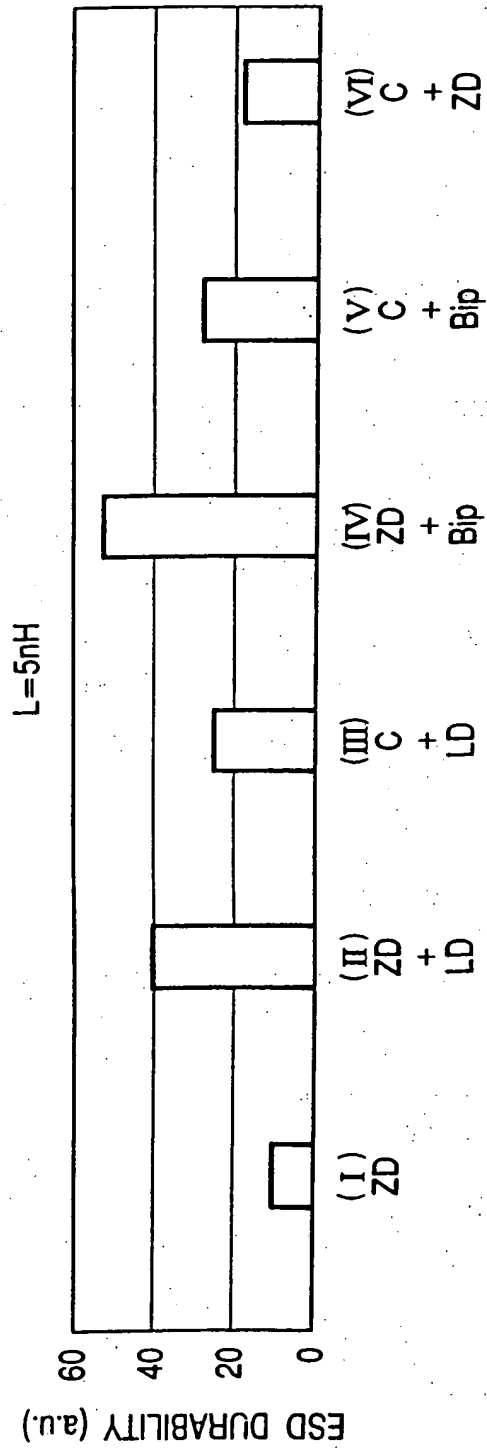


FIG. 32B



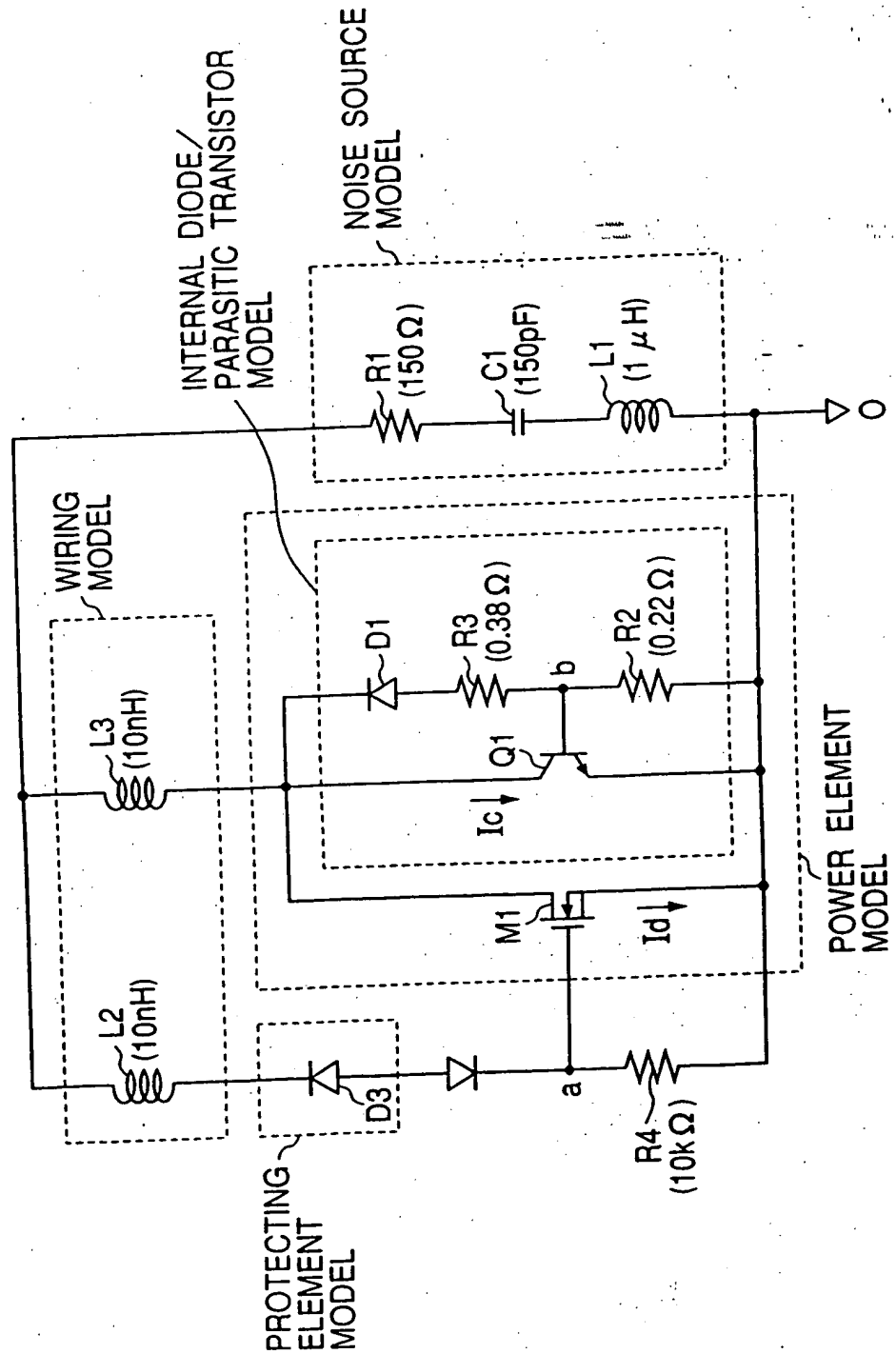
26 / 29

FIG. 33



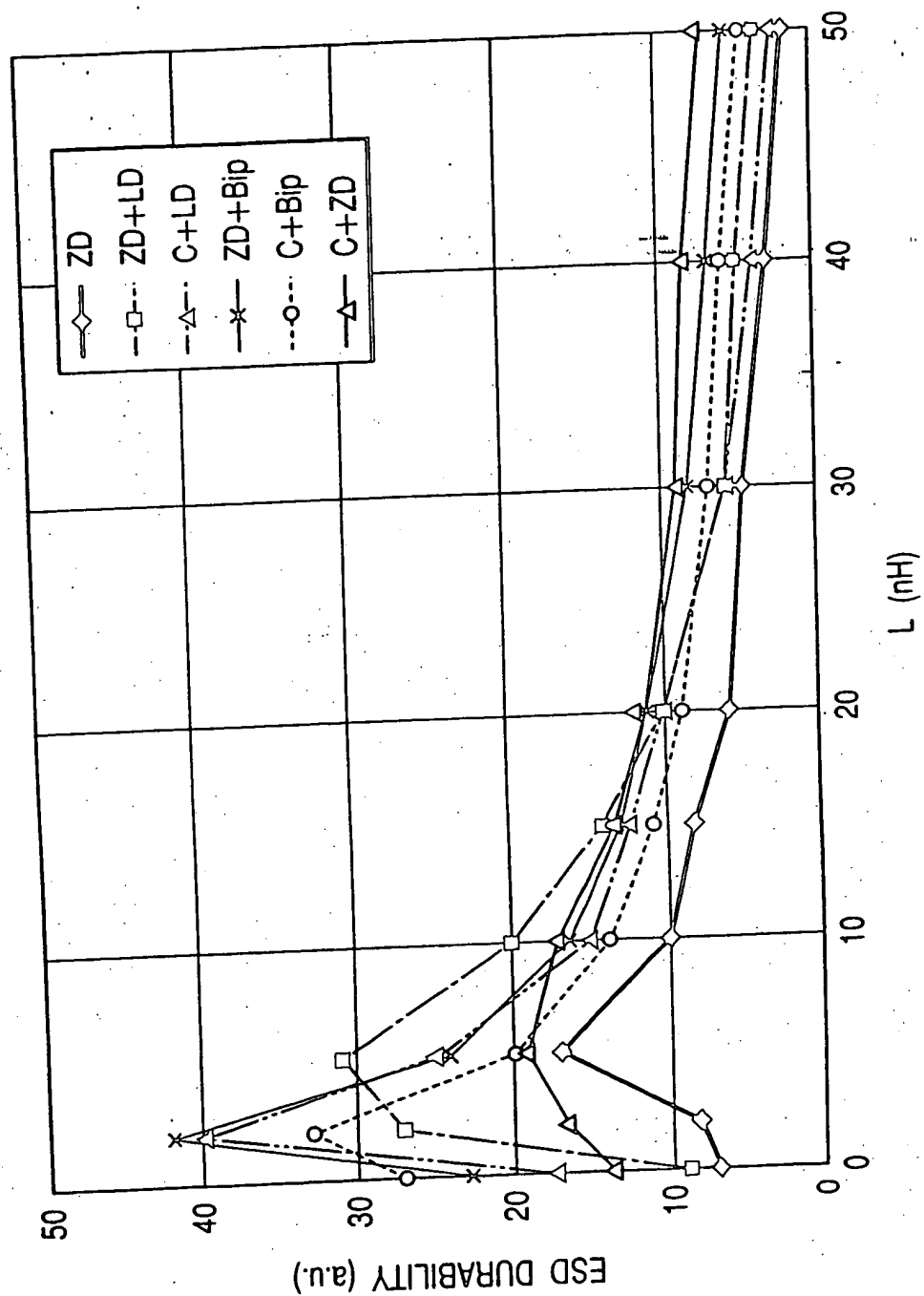
27 / 29

FIG. 34



28 / 29

FIG. 35



29 / 29

FIG. 36A

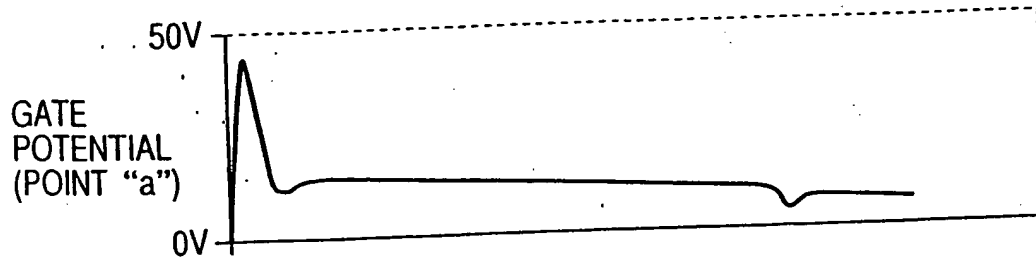


FIG. 36B

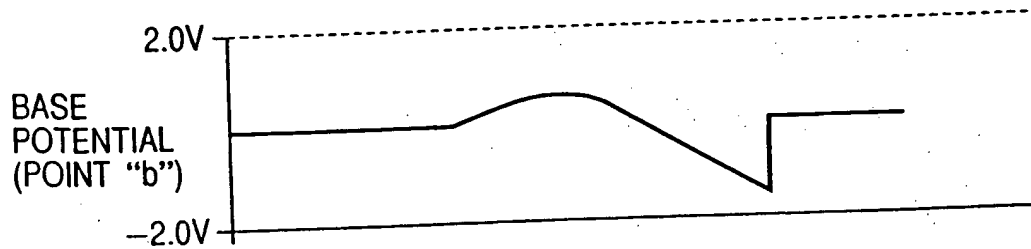


FIG. 36C

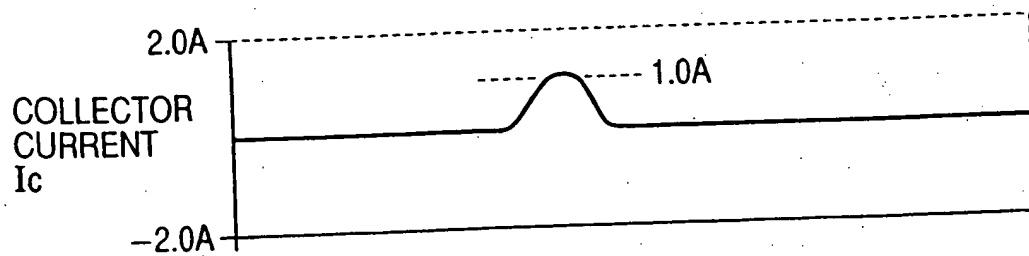


FIG. 36D

